Electronic Supplementary Information

Photonic design of embedded dielectric scatterers for dye sensitized solar cells using full-wave optical simulation

Mahdi Malekshahi Byranvand^a, Ali Dabirian^{b,c,*}, Ali Nemati Kharat^a and Nima Taghavinia^b

^aSchool of Chemistry, University College of Science, University of Tehran, Tehran, Iran

^bDepartment of Physics, Sharif University of Technology, Tehran 14588, Iran

^cPhotovoltaics and thin film electronics laboratory, Ecole Polytechique Federale de Lausanne (EPFL), Rue de la Maladiere 71, Neuchatel 2000, Switzerland

*Corresponding Author: Tel: +41 21 695 42 61

Email: ali.dabirian@epfl.ch



Fig S1. SEM cross-sectional images of TiO_2 film with the estimation of film thickness.



Fig S2. a) Diffuse reflectivity and b) Diffuse transmittance of screen printed layers of silica particles mixed in the TiO_2 paste.



Fig S3. a) Diffuse reflectivity and b) diffuse transmittance of dye-sensitized layers.



Fig S4. Digital photographs of films made from 6 vol% silica particles in the paste a) after and b) before dye loading.

Table S1. Number of dye adsorbed on the different samples. The values are measured by dye desorption using aqueous solution of 0.1 M NaOH and measurement of absorptivity of the dye in the solution.

Number of dye	Roughness factor	Roughness factor
molecule(#/cm ²)*10 ¹⁵		[µm]
16.5	992	94.5
15.7	942	89.8
15.5	931	88.7
15.3	923	87.9
15.2	910	86.7
	Number of dye molecule(#/cm ²)*10 ¹⁵ 16.5 15.7 15.5 15.3 15.2	Number of dye Roughness factor molecule(#/cm²)*10 ¹⁵ 992 16.5 992 15.7 942 15.5 931 15.3 923 15.2 910



Fig S5. IPCE spectra of reference cell (T) and the cell with 6 vol % of spherical silica particles in normal and inverse illumination along with the case that a scattering layer is applied to the rear-side of the cathode.